



An experimental apparatus and diagnostics for the characterization of high-voltage surface flashover in large-scale pulsed power conditions

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Motivation

- Characterize anode-initiated flashover in vacuum
 - Engineer a repeatable flashover location
 - Explore and identify the indicators of the breakdown event
 - Measure breakdown with a high degree of accuracy

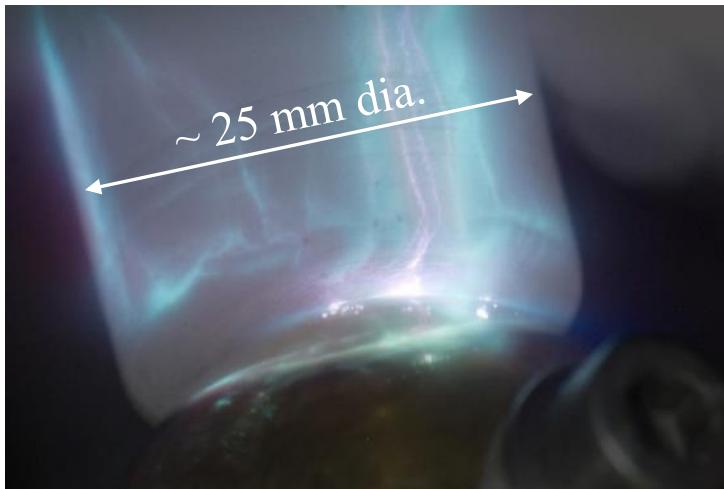
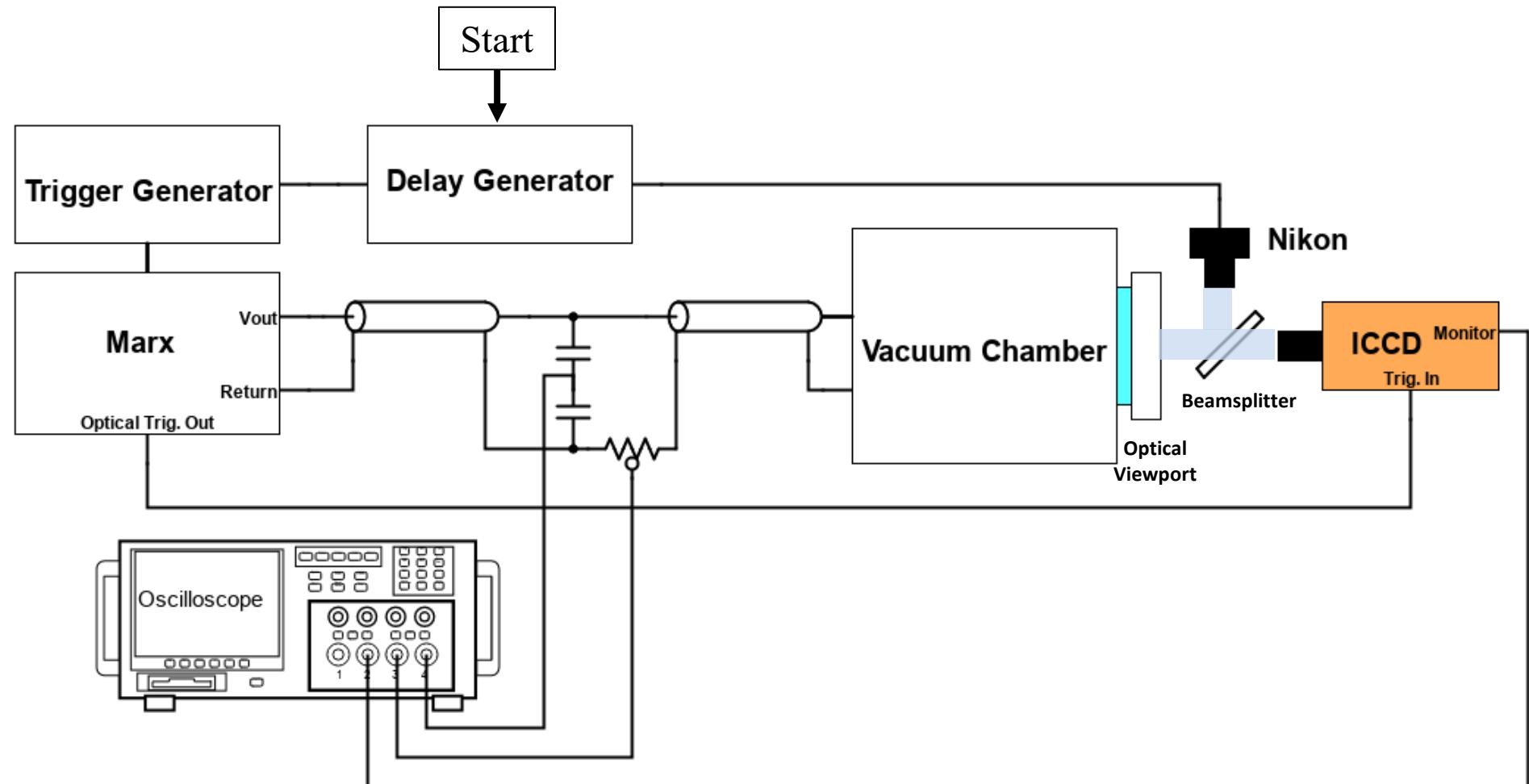


Image of pulsed breakdown of high-voltage vacuum feed-through initially used in experimental setup. (~ 240 kV)



Time integrated image of lateral surface flashover with branching primarily reaching towards the cathode. (~ 240 kV)

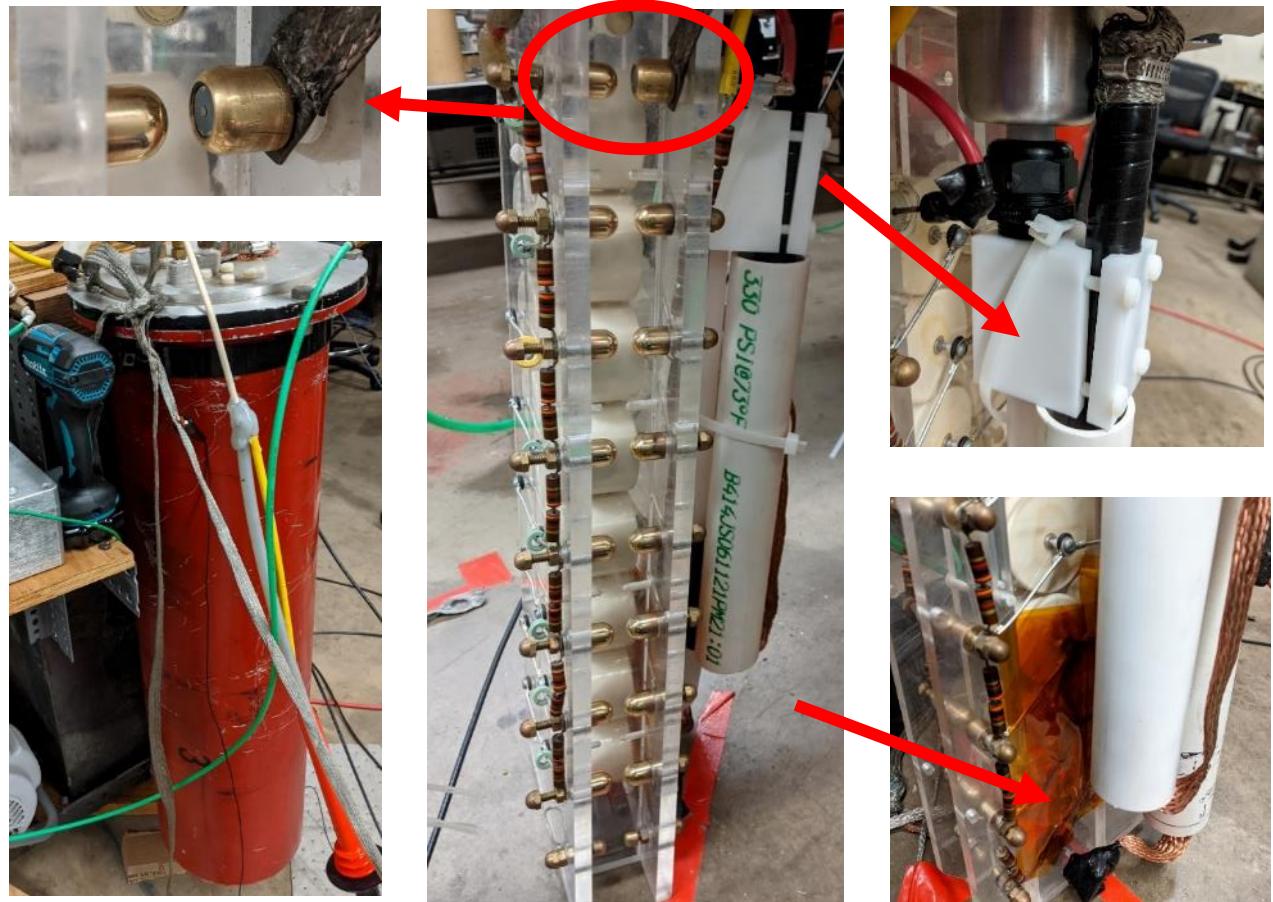


Pressurized Marx

- 16 psig N₂
- Triggered First Gap
- 8 Stages
 - 5.4 nF / Stage
- 675 pF Erected
- Negative Charge
 - Typical (-)30 kV
- Positive Discharge
 - ~18 ns Rise Time
 - > 180 kV Output

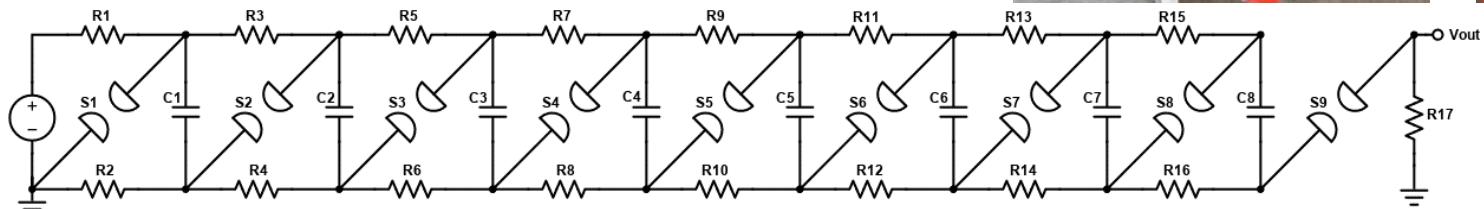
Output

- Internal 2.2 k Ω Shunt
- (System) ESR 30 Ω
- (System) ESL 1.8 μ H

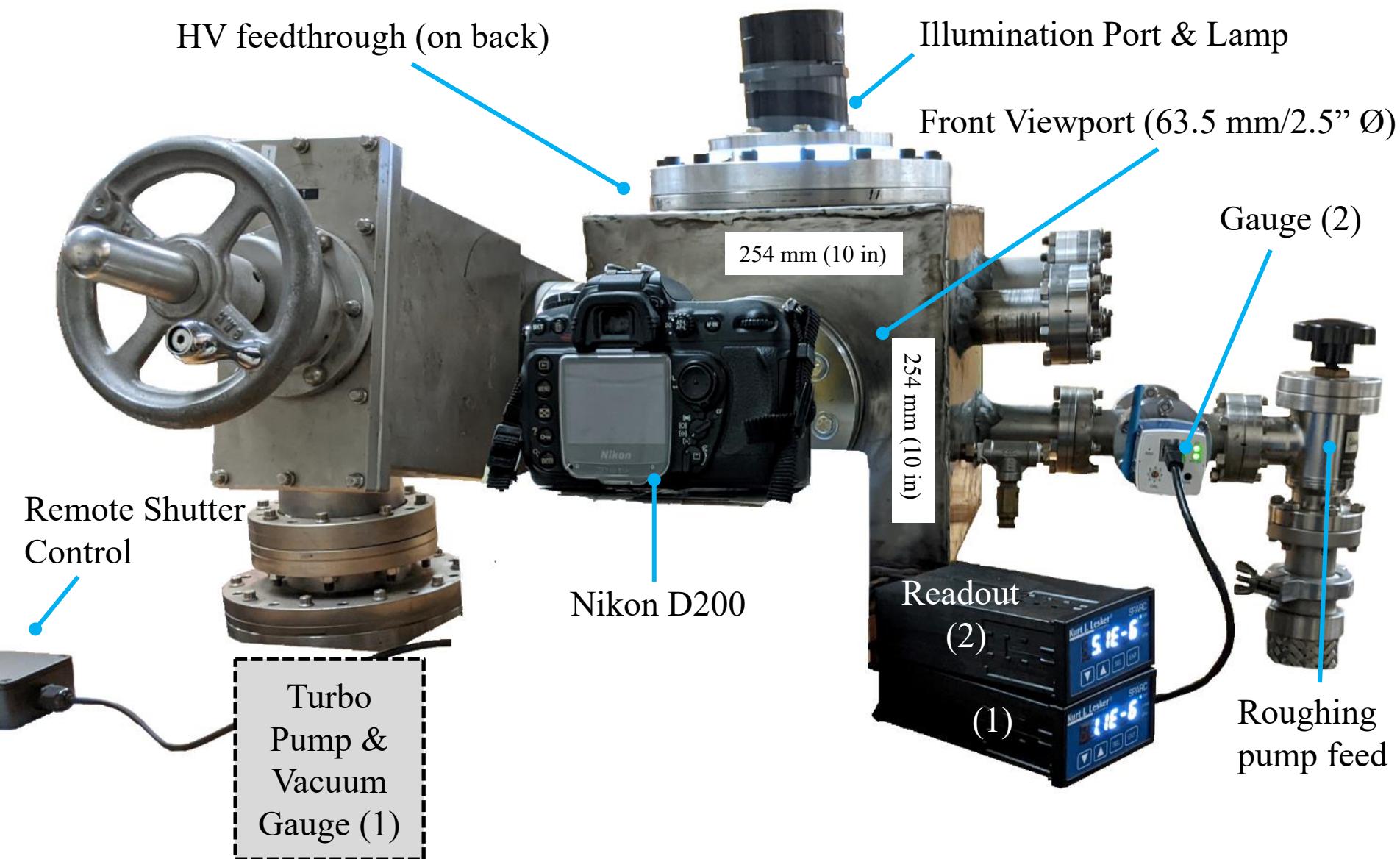


Top: Selected Image of Marx Generator

Left: Corresponding Schematic

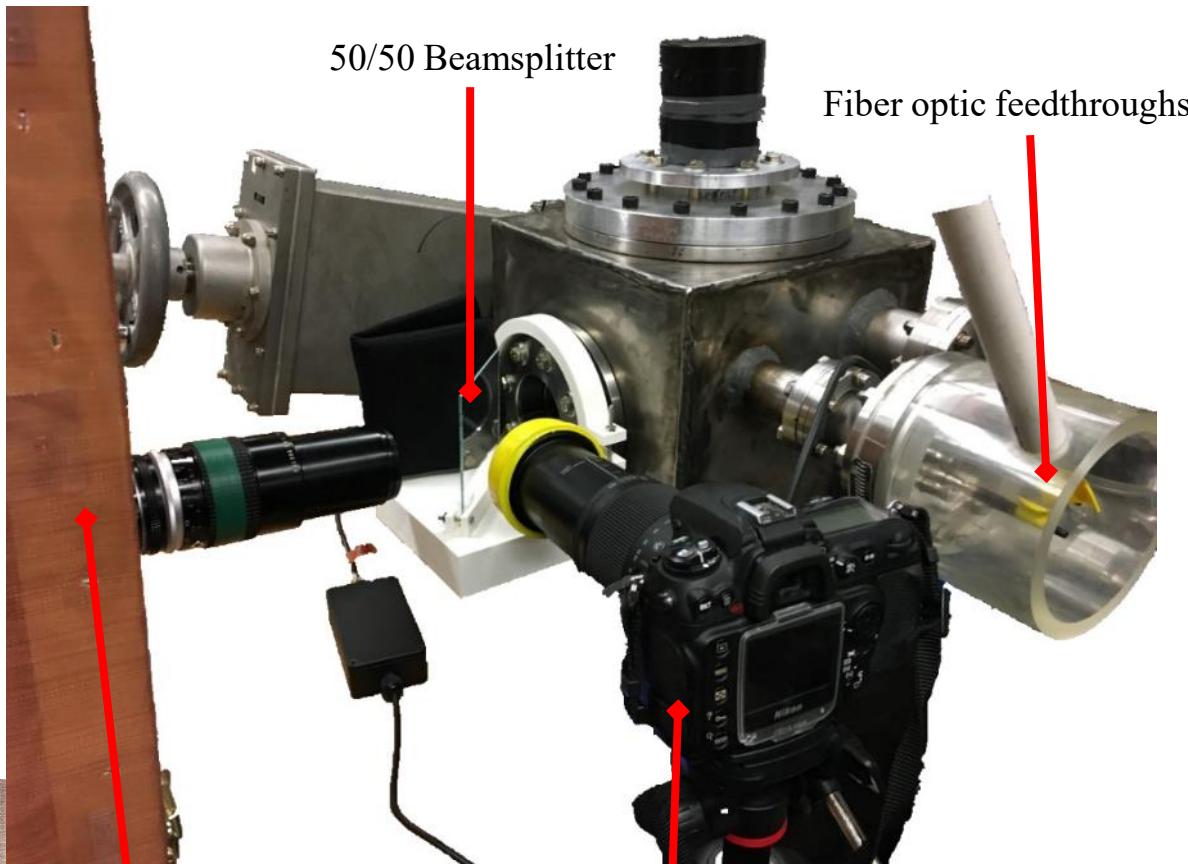
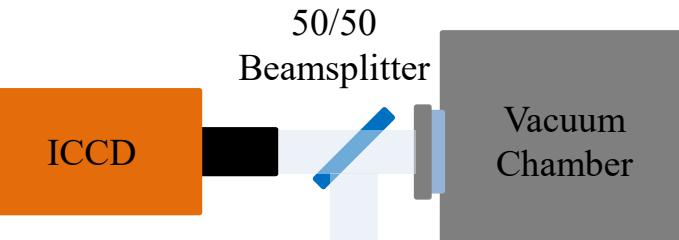


Flashover Chamber (R.0)



Optical Imaging Apparatus

Top-Down View of Imaging Apparatus



Princeton Pi-MAX 4

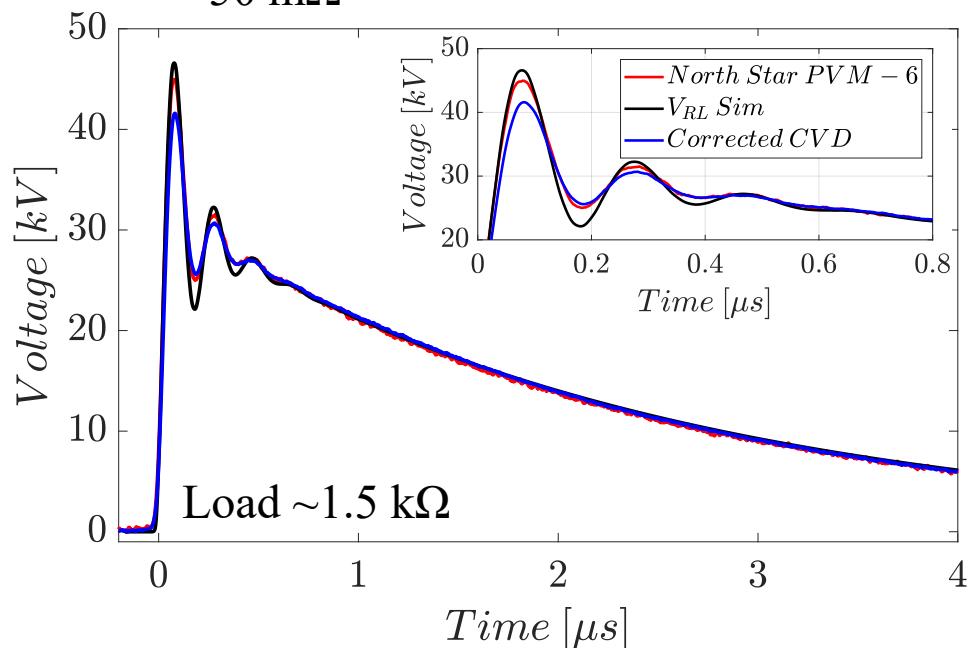
- Intensified CCD
- Sub-500 ps gate capable

Nikon D200
Sigma 18-300 mm F3.5-6.3 DC Macro
Edmund Optics 75 mm x 300 mm FL
(VIS 0 Ar. Coated, Achromatic Lens, 88-594)



Current Viewing Resistor
 $\sim 50 \text{ m}\Omega$

Capacitive Voltage Divider



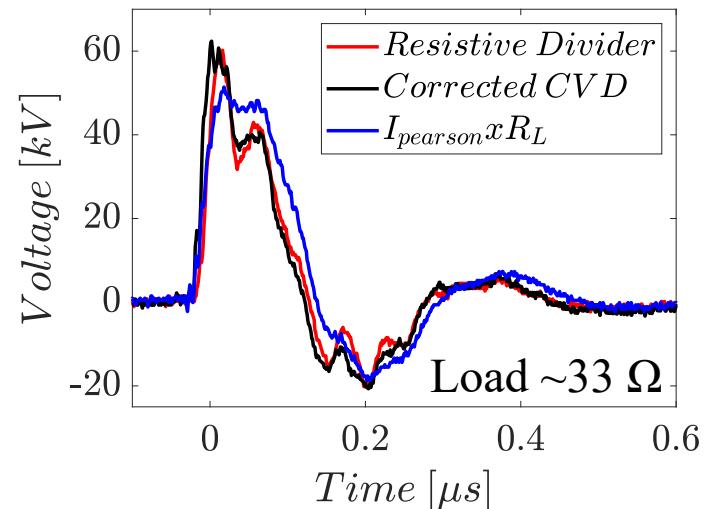
CVR Calibration

- Pearson 110
- Pearson 6585

CVD Calibration

- NorthStar PVM-6
- Current * Load

$$V_{in}(t) = \frac{1}{a} V_m(t) + \frac{1}{\alpha \tau} \int_0^t V_m(t') dt'$$



Insulator Testbed



Physical Dimensions

Insulator

79.38 mm (3.125 in) Wide

25.40 mm (1.00 in) Tall

Wedge

45 Degrees

6 mm Vertical

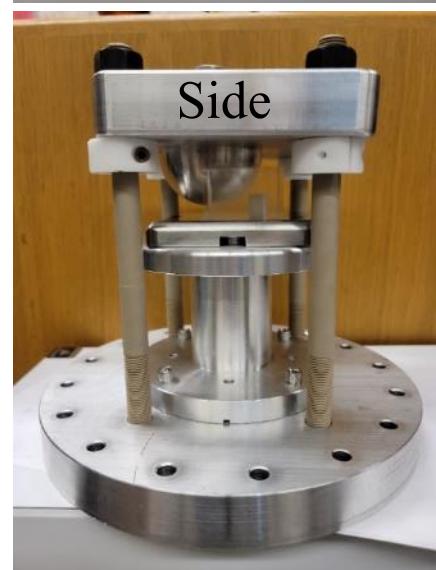
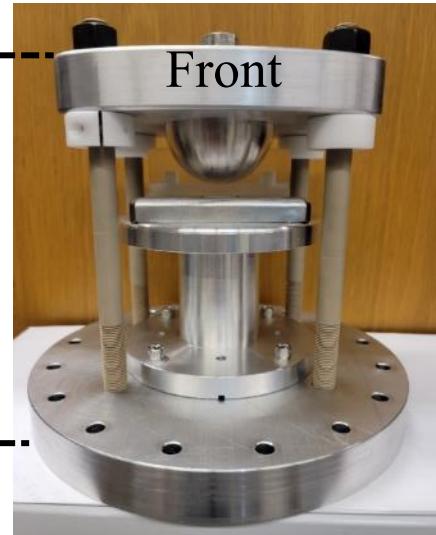
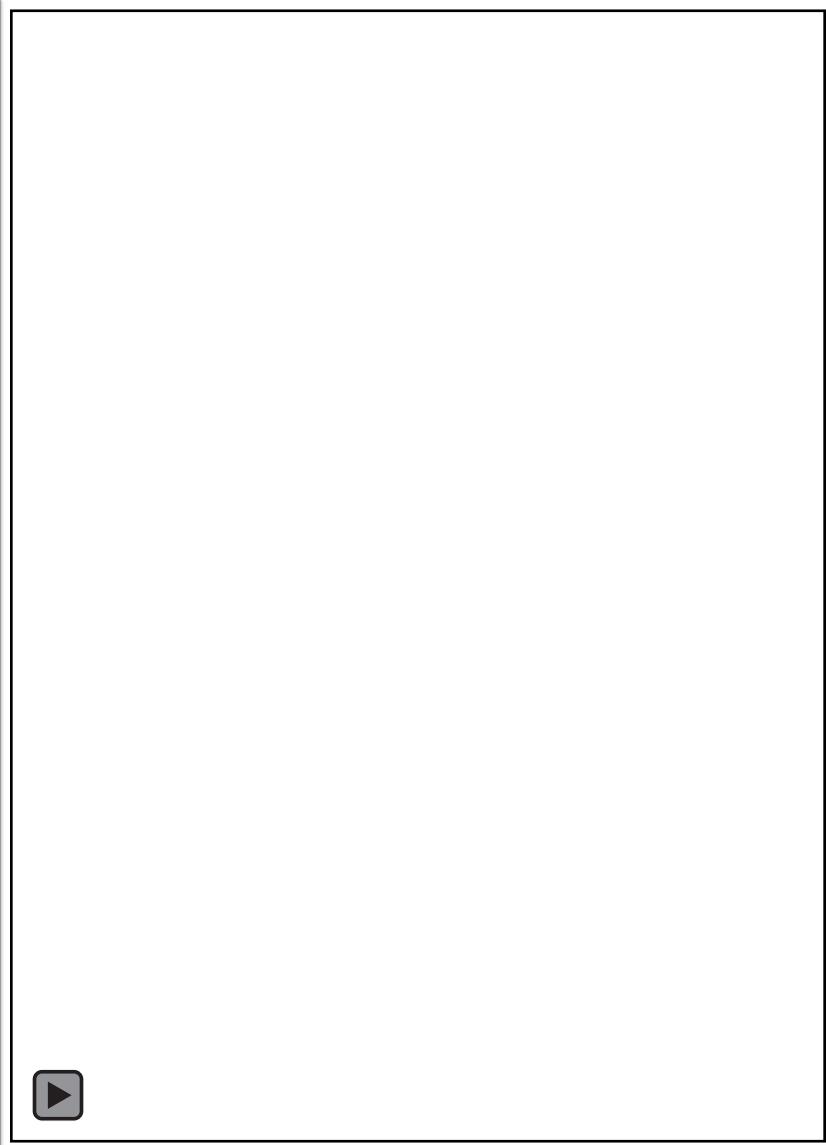
Anode

30 mm radius

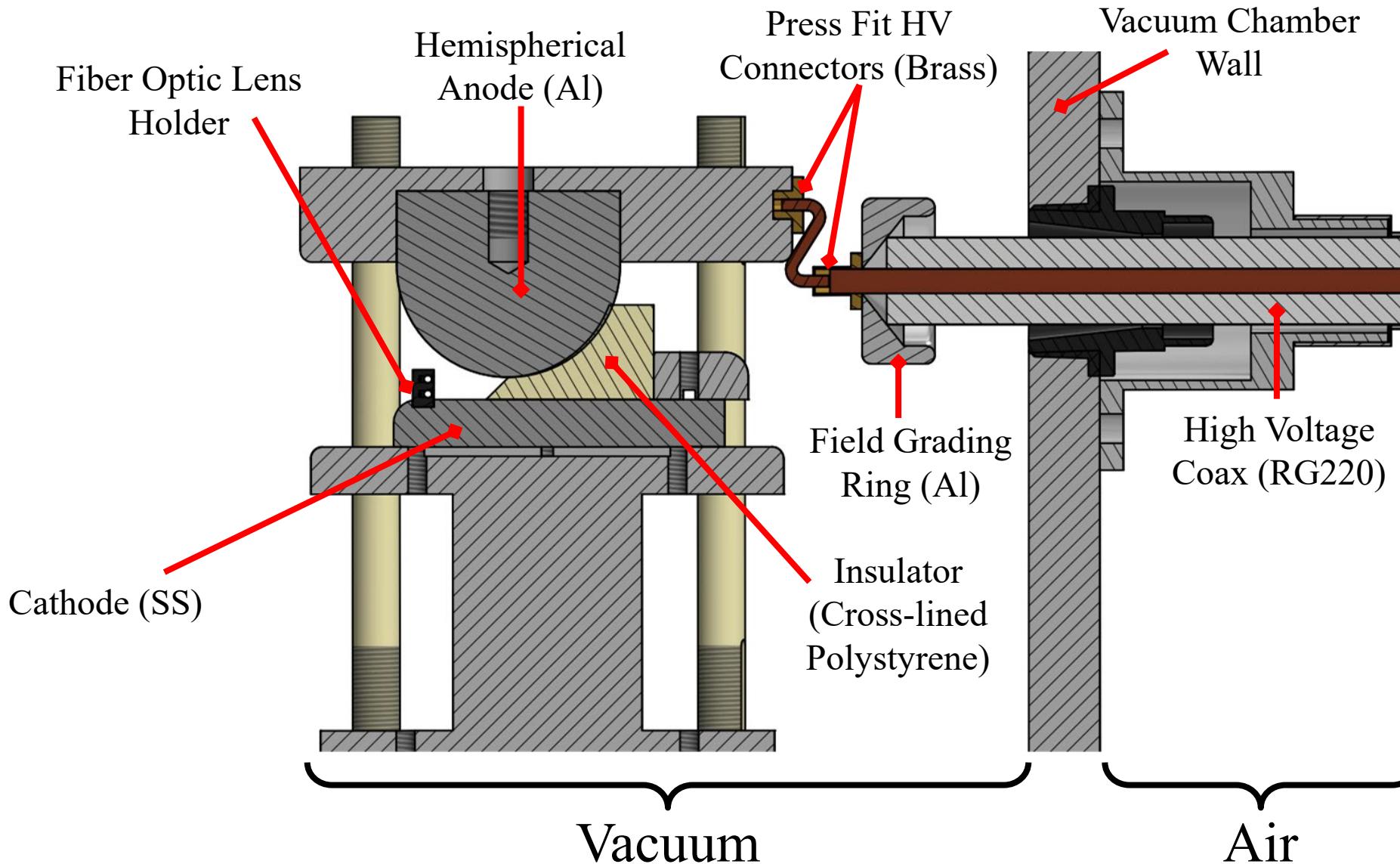
Cathode

95.25 mm (3.75 in) Wide

88.90 mm (3.50 in) Deep



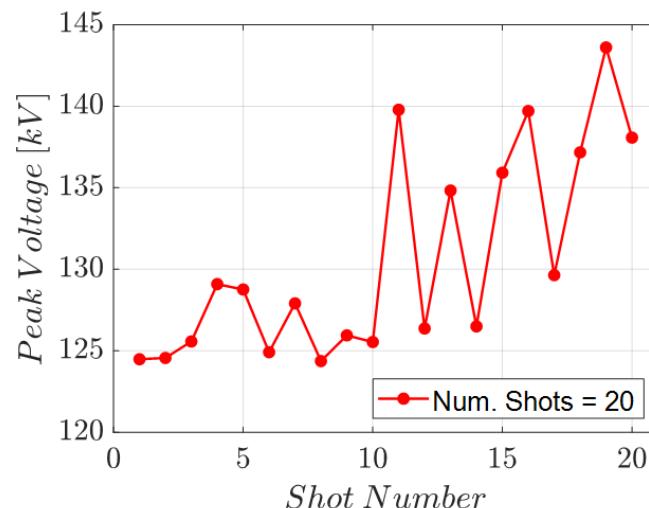
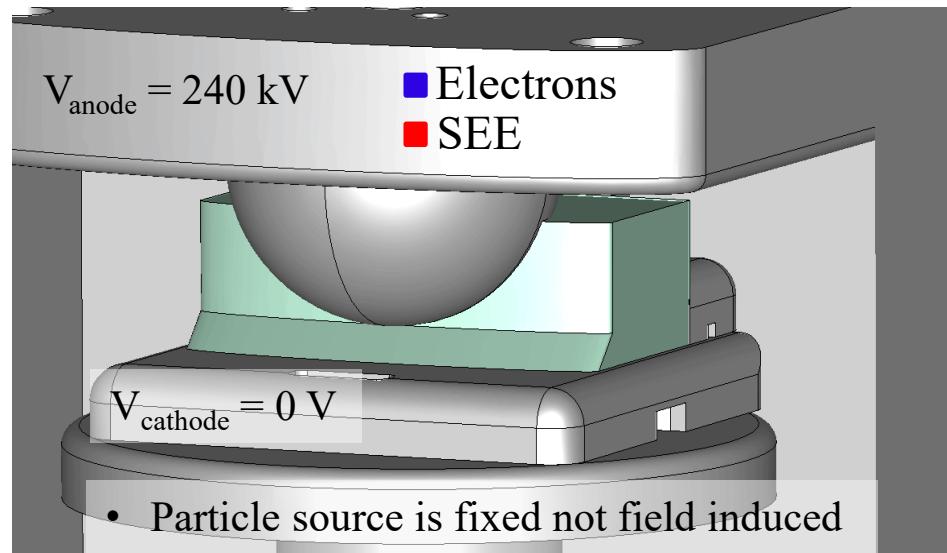
Insulator Testbed Cross-Section



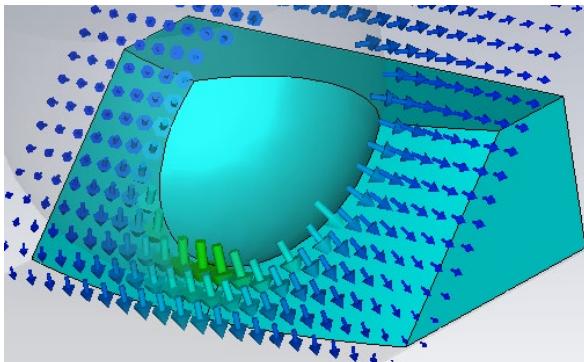
1st Gen. Insulator Topology



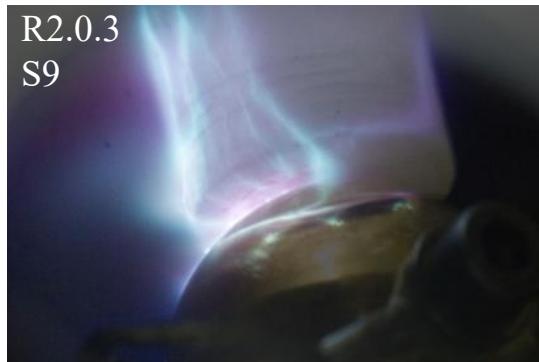
- Initial results exposed design limitation, SEEA along front vertical face, in the first iteration of the insulator topology



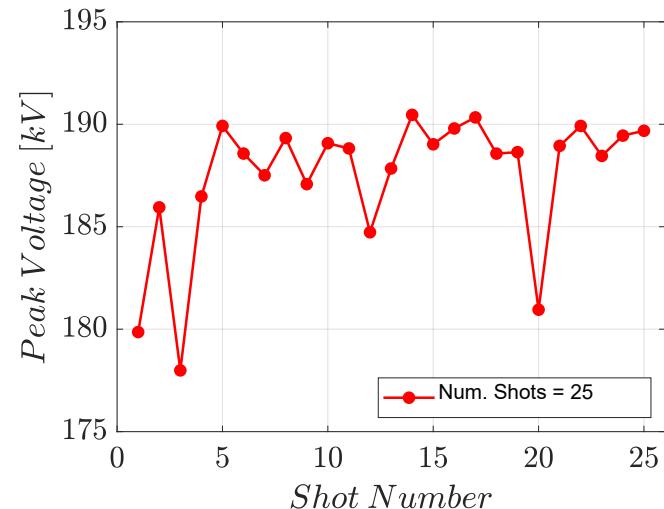
- Second insulator topology pushed breakdown voltage much higher and exposes limitation of the current insulator apparatus



(Simulated) Electric Field

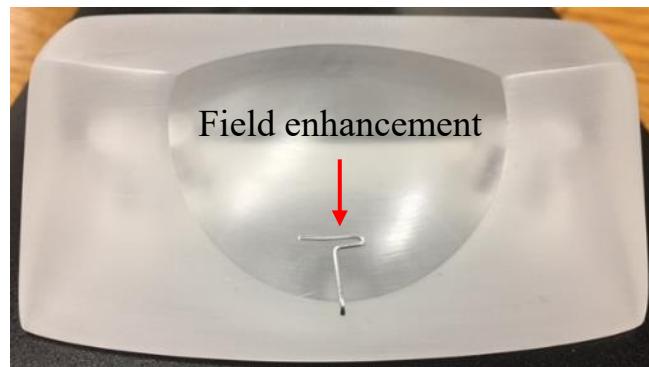


R2.0.3
S9
Breakdown along HV feedthrough



Field Enhancement

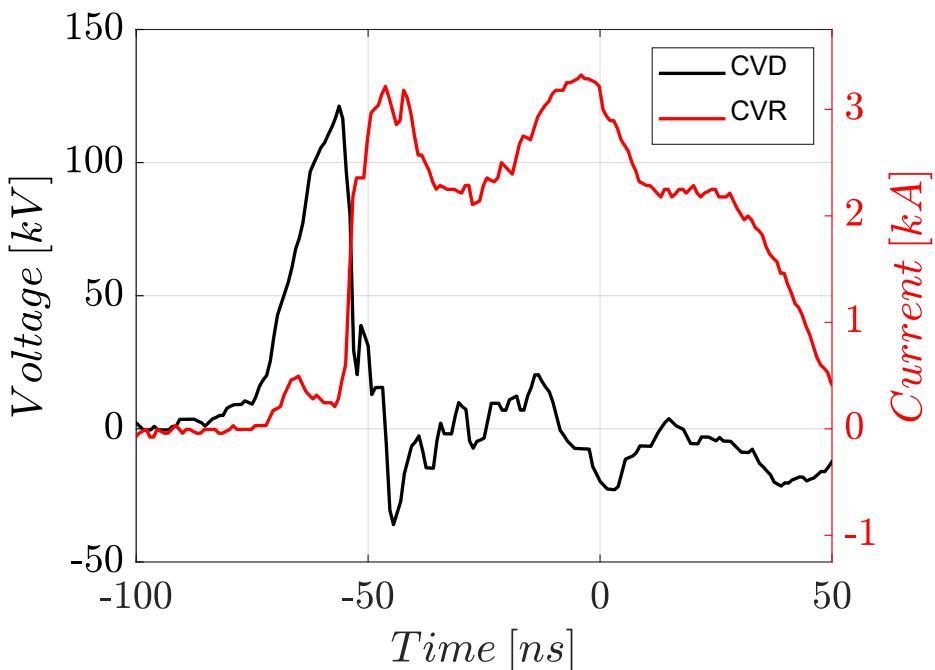
- Field enhancement at anode triple junction simulates a preferential breakdown locations due to a flaw
- Material: Aluminum wire 0.02" diameter



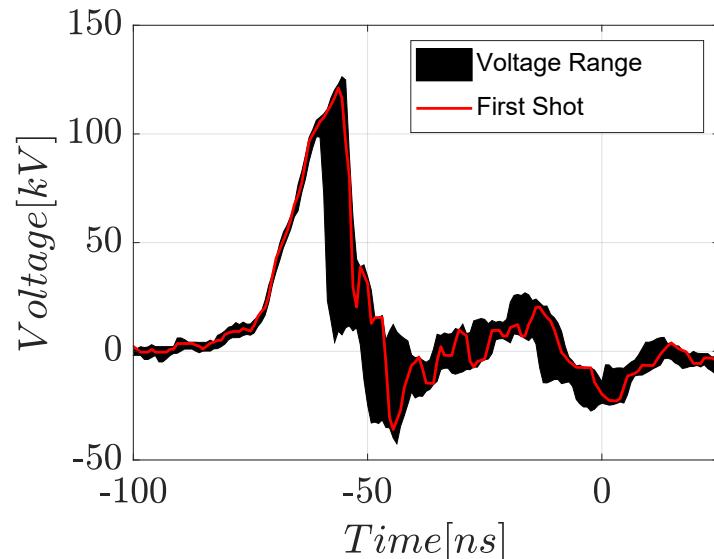
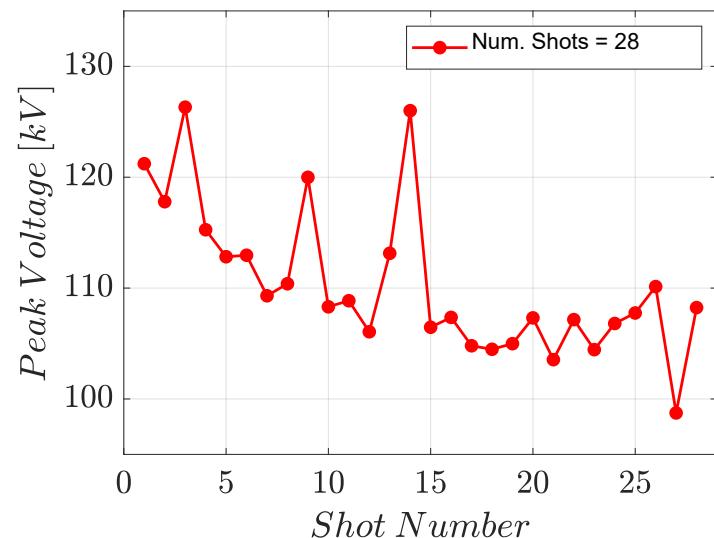
Typical Waveforms

Statistics (R2.2.7.1)

- Rise Time = 13.36 ± 1.4 [ns] (std.)
- $V_{peak} = 110.4 \pm 6.7$ [kV] (std.)
- V_{peak} Ranges (98.7 to 126.3) [kV]

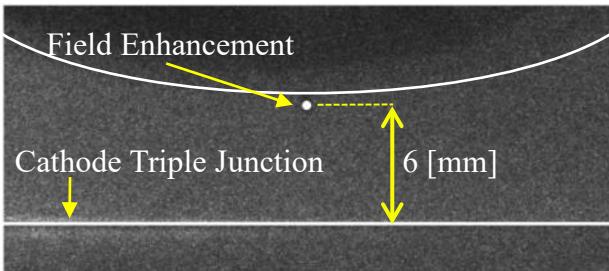


CVD: 500 mV/div, 23 dB of attenuation
CVR: 2.5 V/div, 23 dB of attenuation



Temporally Resolved Imaging

Reference Image

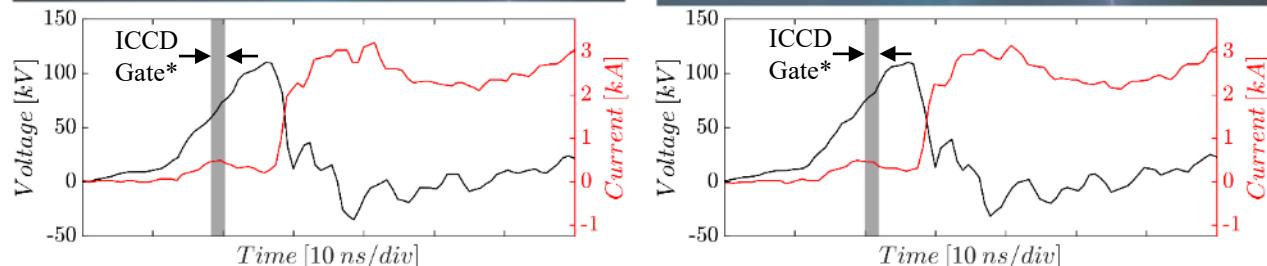
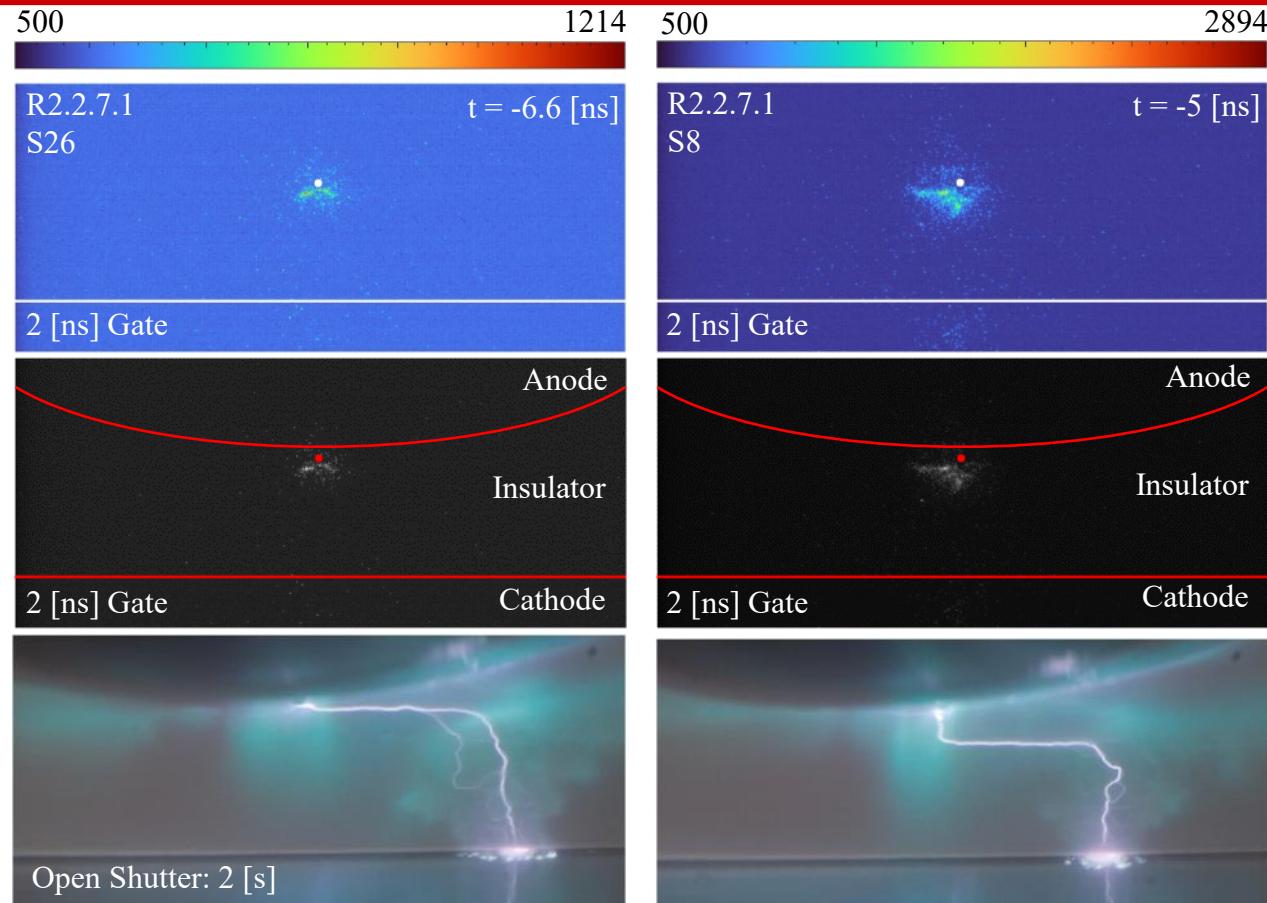


ICCD Settings

Gating Time: 2 [ns]

Gain: 90

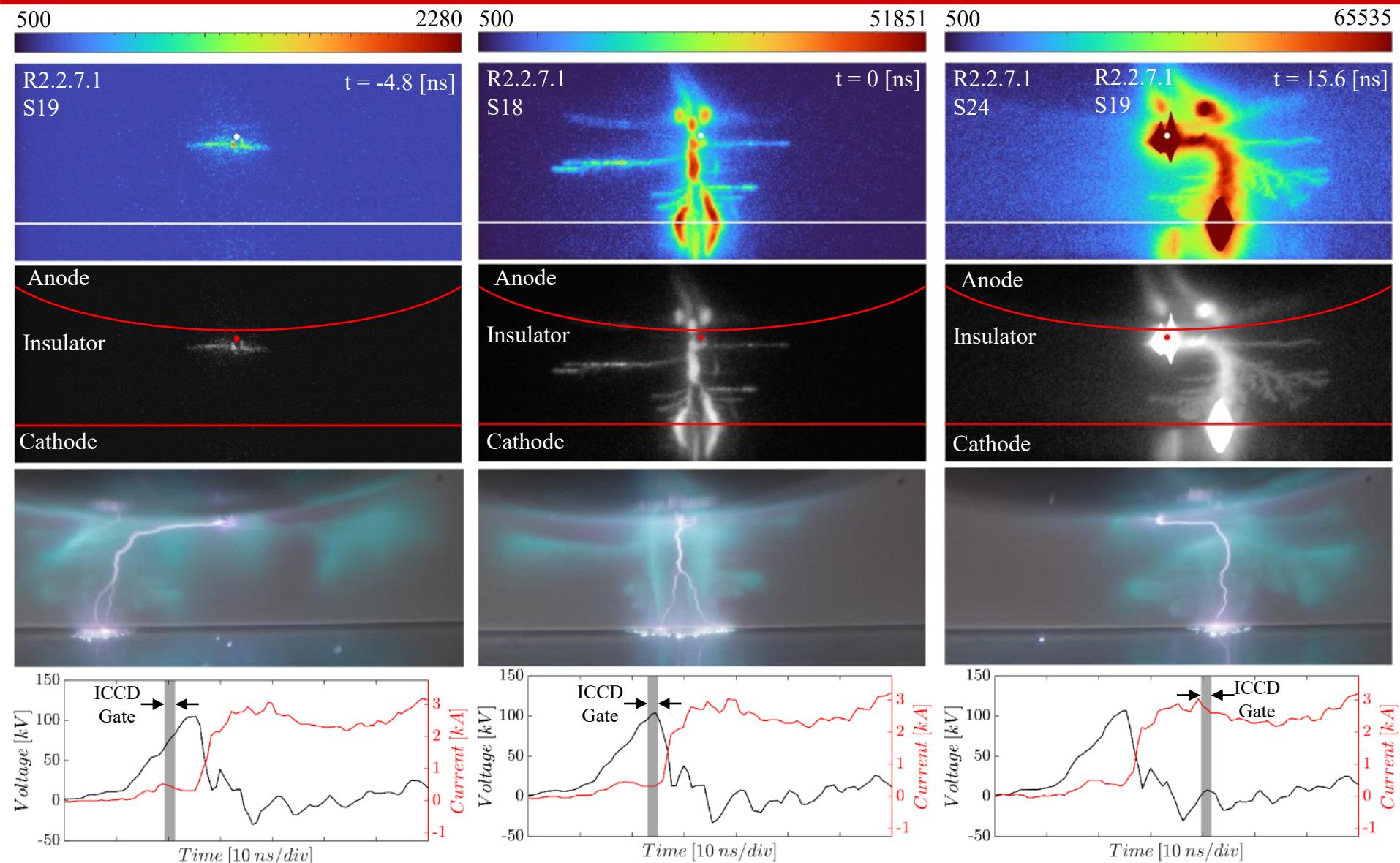
F#: F/4.5



- Imaging supports anode-initiated theory
- *Small uncertainty exist in exact ICCD gating given monitor pulse is internally delayed ± 3 [ns] with respect to photocathode gating



Temporally Resolved Imaging



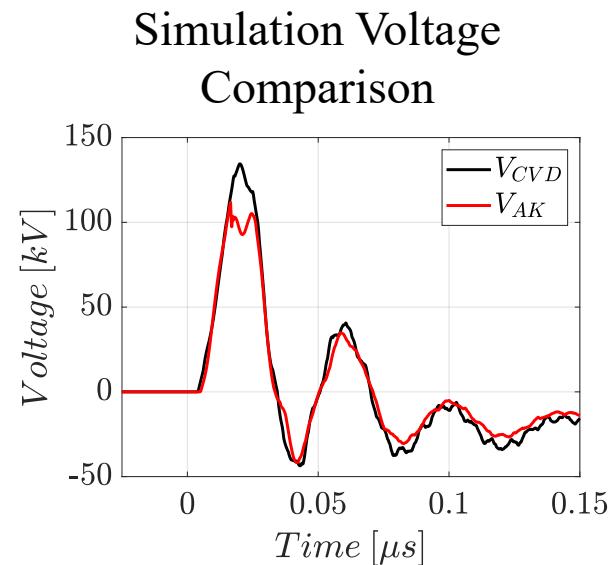
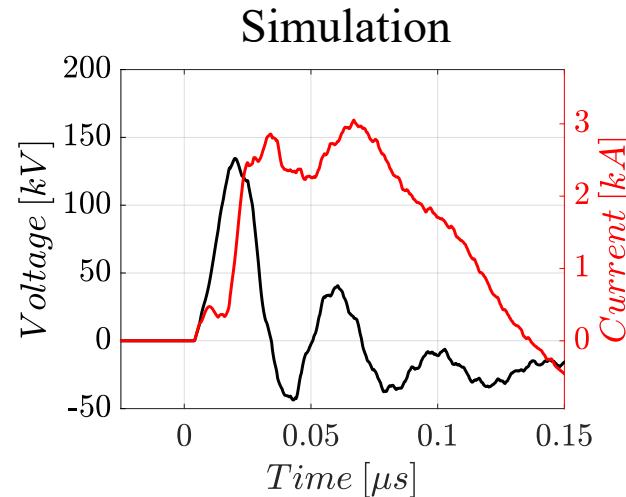
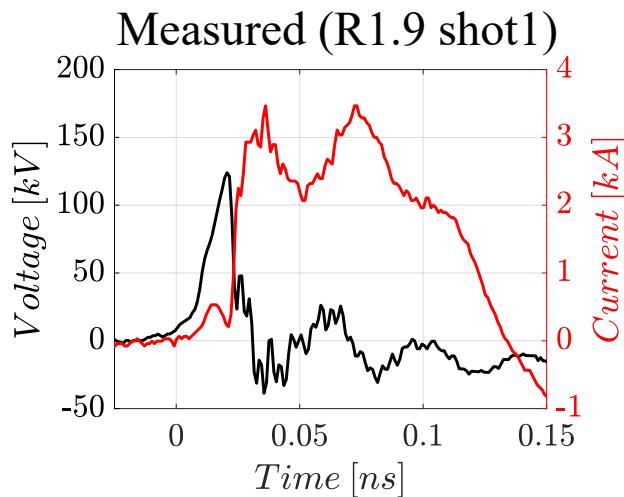
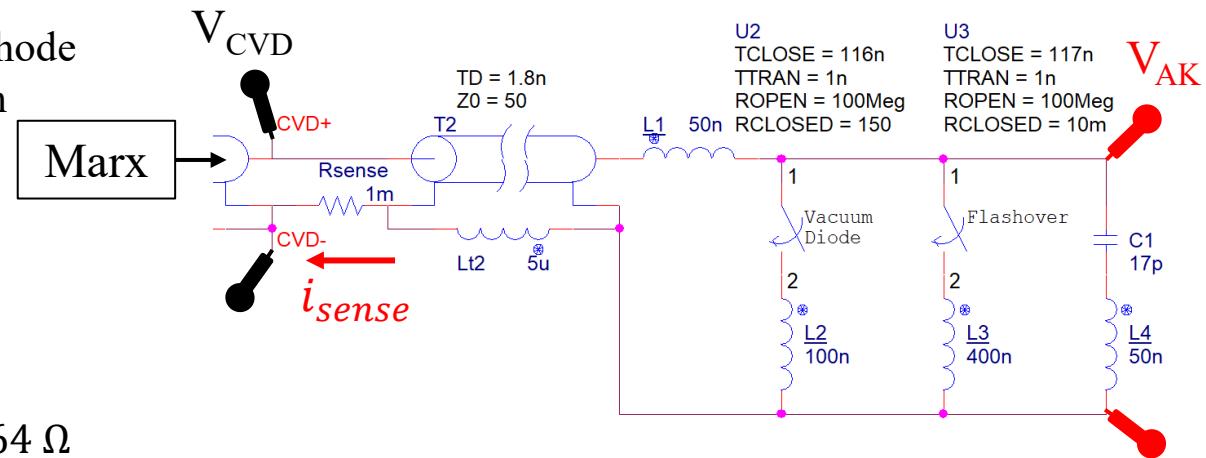
Electrical Model

Child-Langmuir diode is formed, pre-breakdown, between all anode and cathode surface area including HV feedthrough

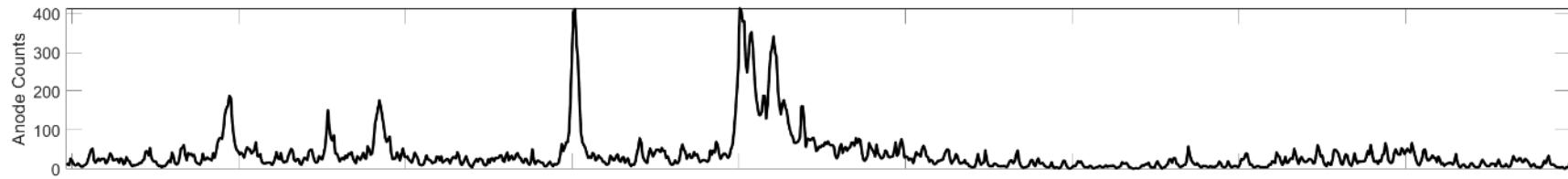
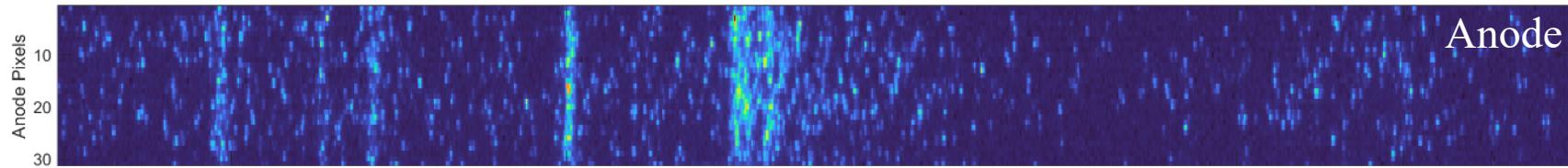
$$d = 2 \text{ [cm]}$$

$$V_0 = 0.150 \text{ [MV]} \quad A = 27 \text{ [cm}^2]$$

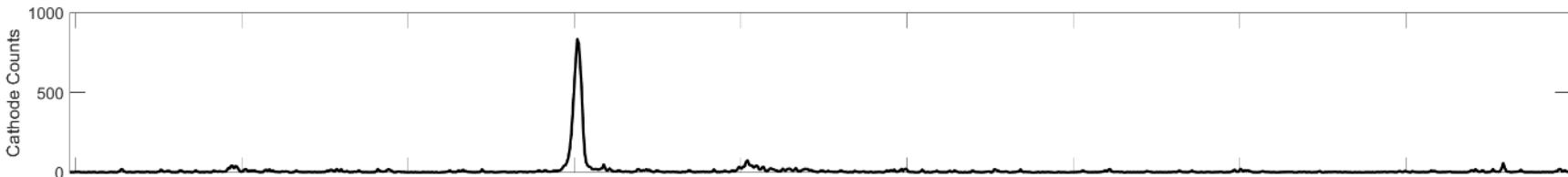
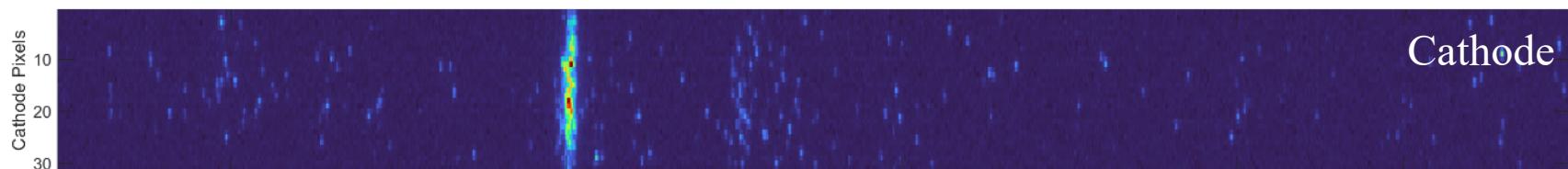
$$Z_{VD} = 429 \frac{[d(\text{cm})]^2}{A(\text{cm}^2)[V_0(\text{MV})]^{1/2}} = 164 \Omega$$



Raimi Clark, session (4O-A) on Thursday the 16th



— — — — — $\sim 465 \text{ nm center wavelength, } \sim 45 \text{ nm window}$ — — — — —



Conclusions

- Conclusions:
 - Early-stage light emission originates near anode
 - Discharge develops from anode to cathode
 - Observed branching and “unsuccessful” streamer fronts
 - Emission tends to follow insulator machining defects (likely exacerbated by the specific flashover geometry)
- Future Work:
 - Develop the next generation of insulator topology to localize the flashover event to the point of interest
 - Investigate the behavior of different materials.
 - Gather additional temporally resolved images to further characterize flashover over time

